T0h2h0" 09hTh860

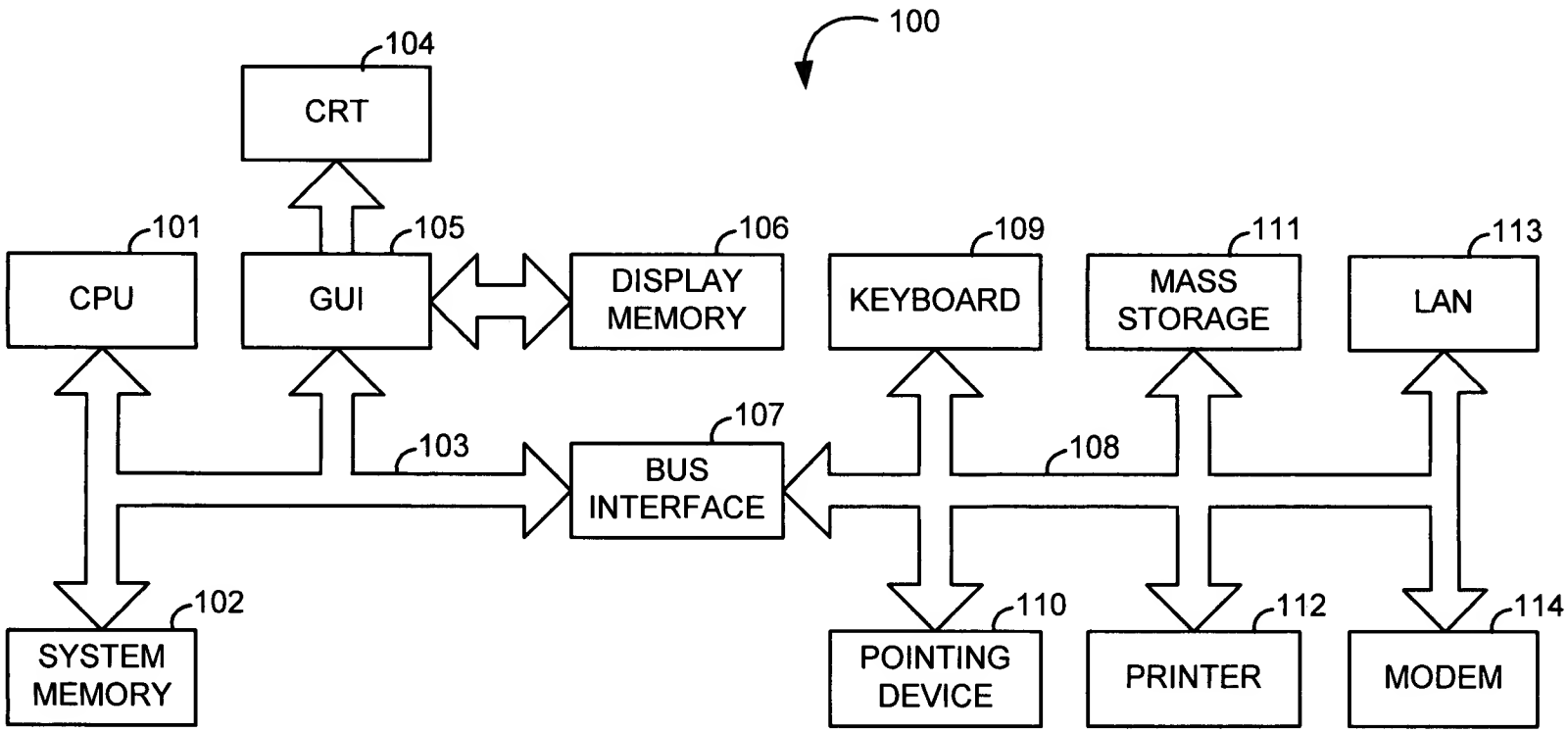

FIG.1

TOh2hO" O9hTh86O

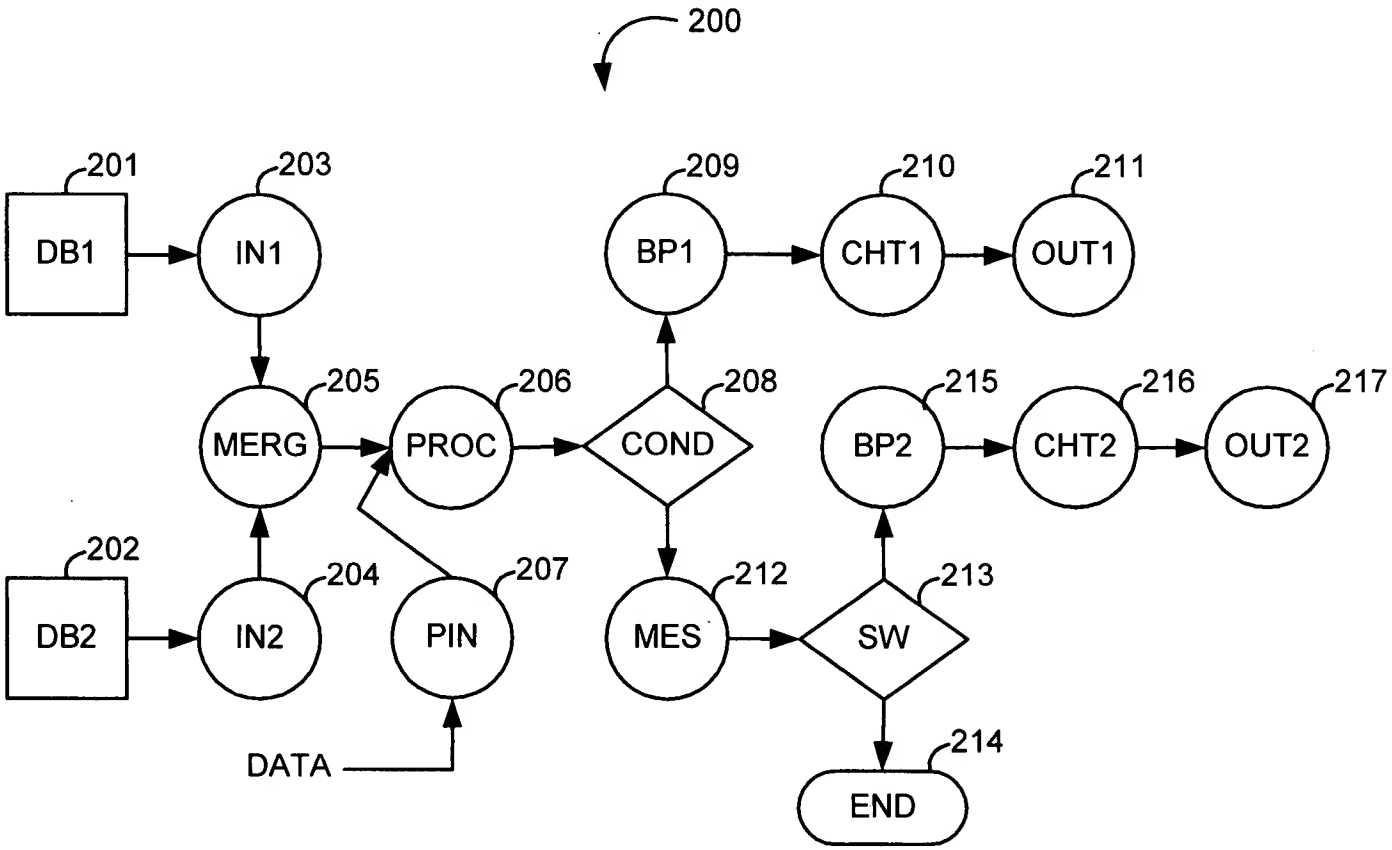

FIG.2

T0h2h0" 09hTh860

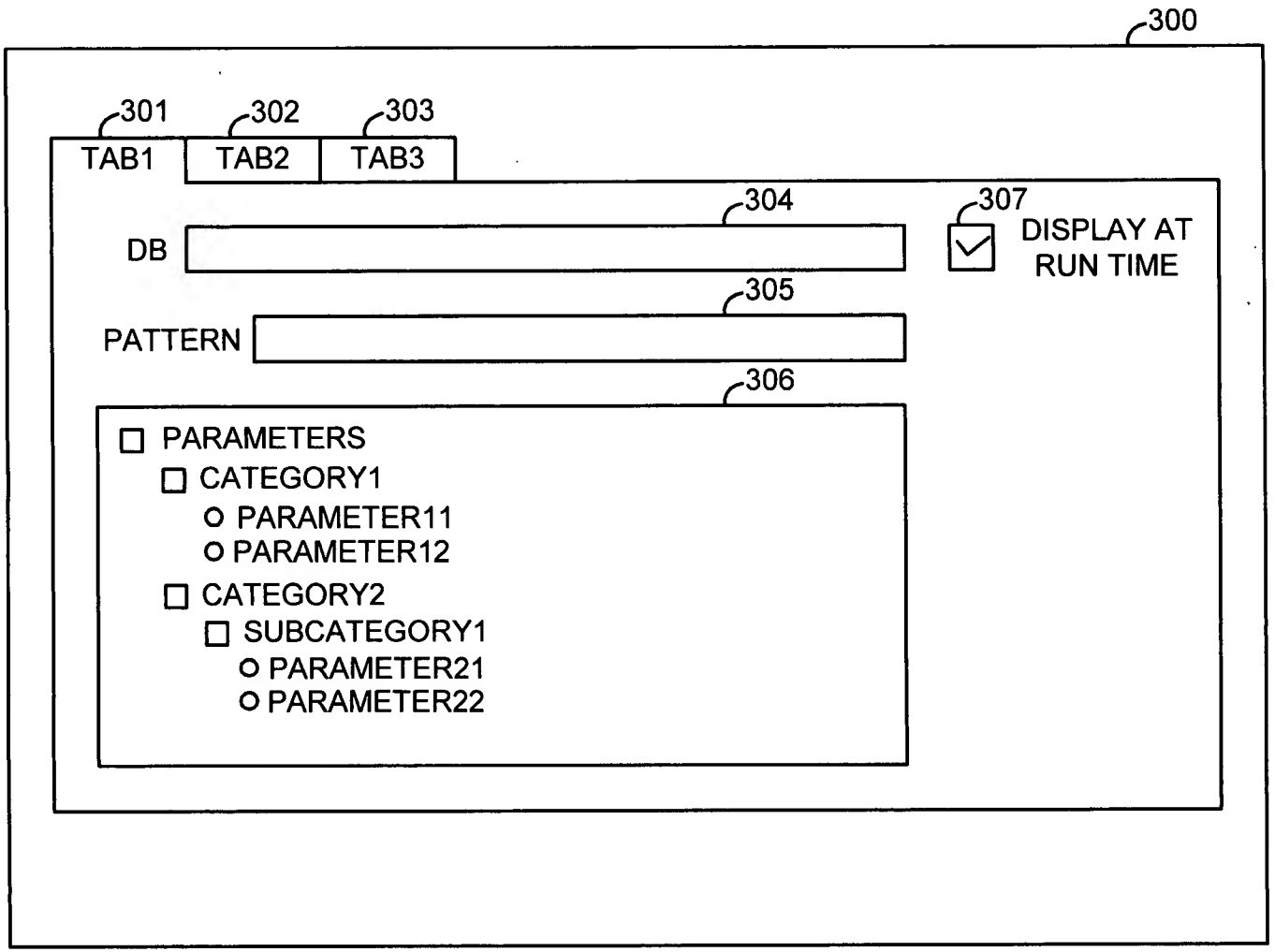

FIG.3

T0h2h0" 09hTh860

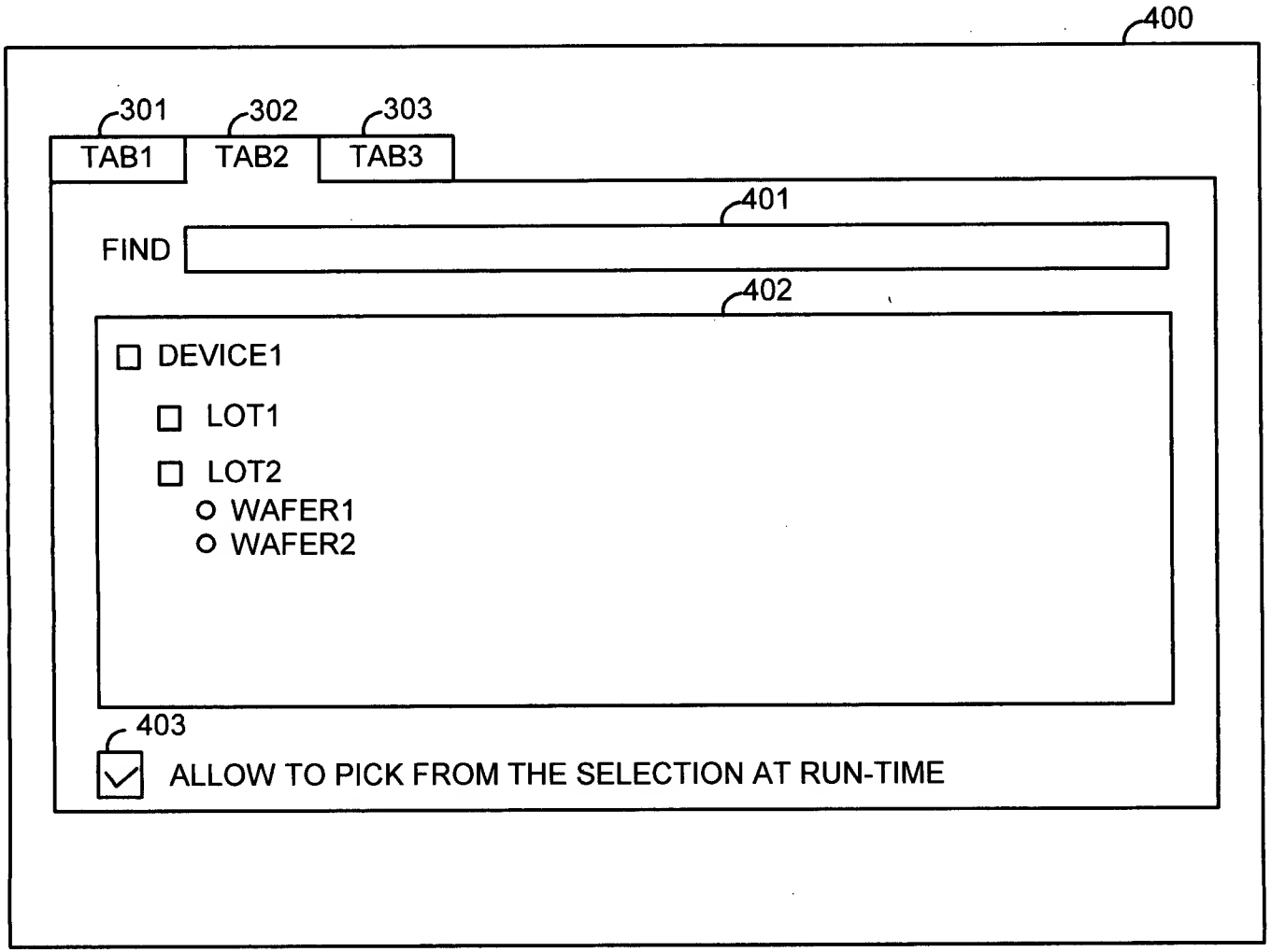

FIG.4

T0h2h0"09hTh860

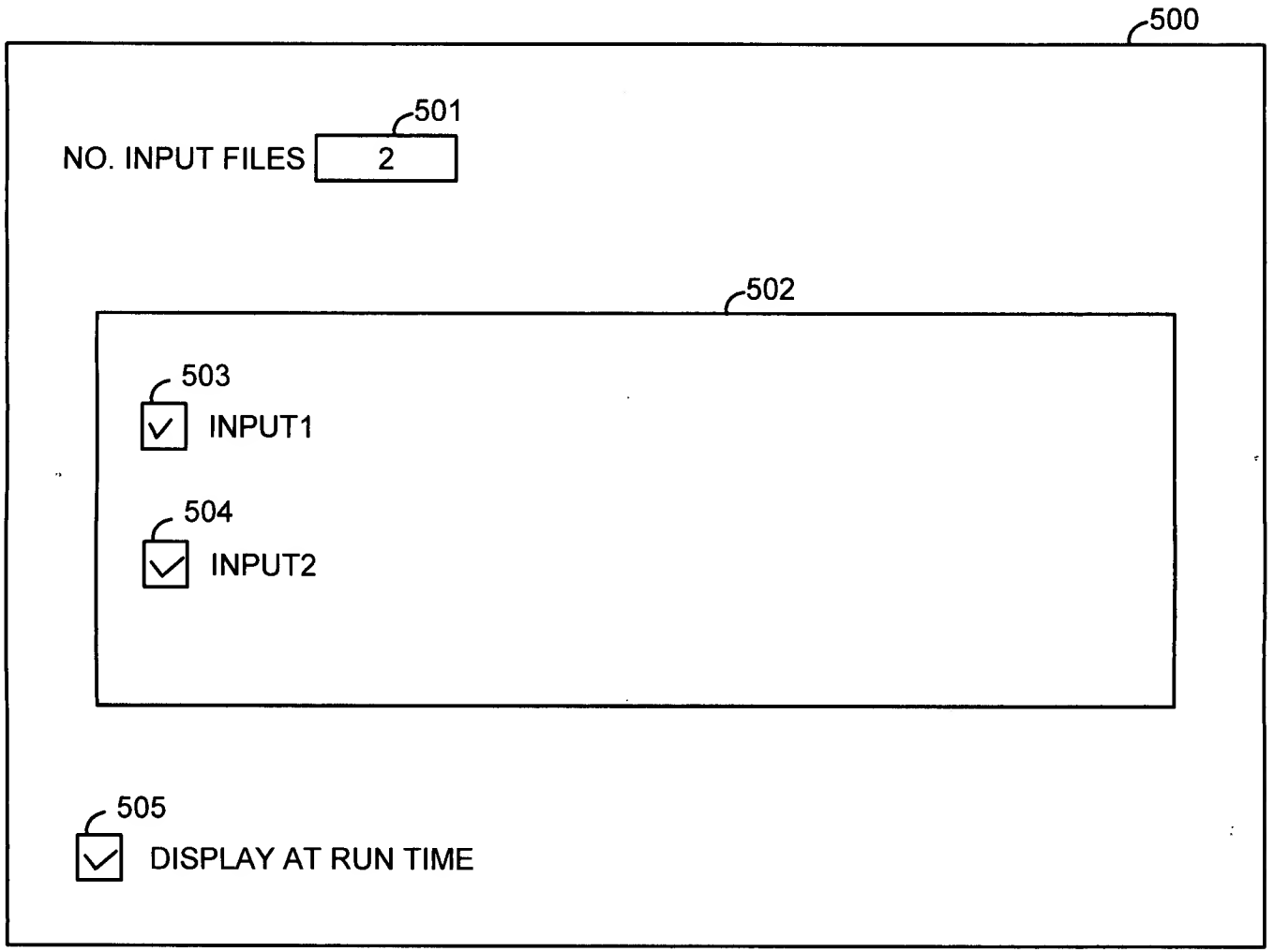

FIG.5

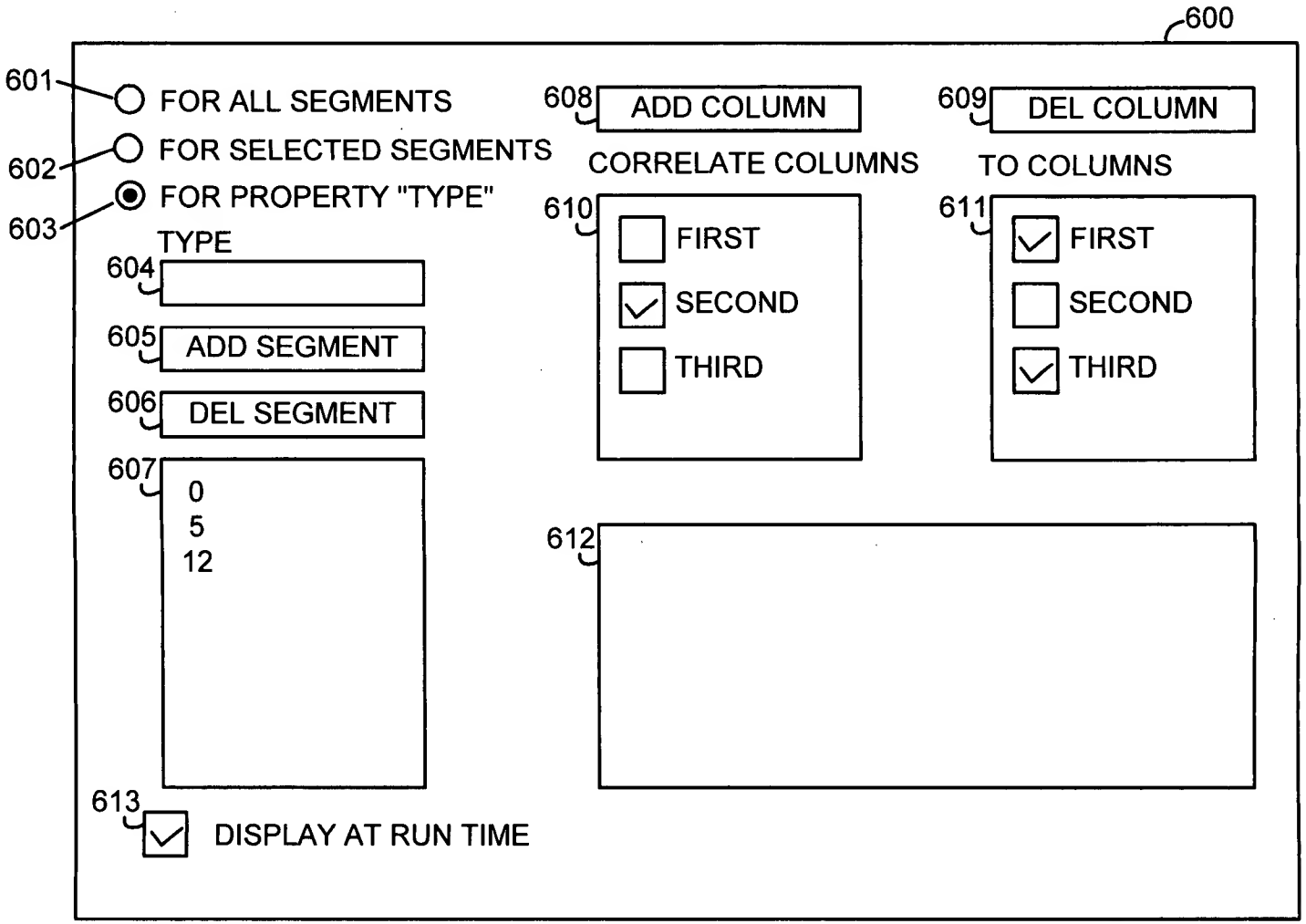
600
601
FOR ALL SEGMENTS
602
FOR SELECTED SEGMENTS
603
FOR PROPERTY "TYPE"
TYPE
604
605
ADD SEGMENT
606
DEL SEGMENT
607
0
5
12
608
ADD COLUMN
609
DEL COLUMN
CORRELATE COLUMNS
TO COLUMNS
610
FIRST
SECOND
THIRD
611
FIRST
SECOND
THIRD
612
613
DISPLAY AT RUN TIME

FIG.6

T0h2h0" 09hTh860

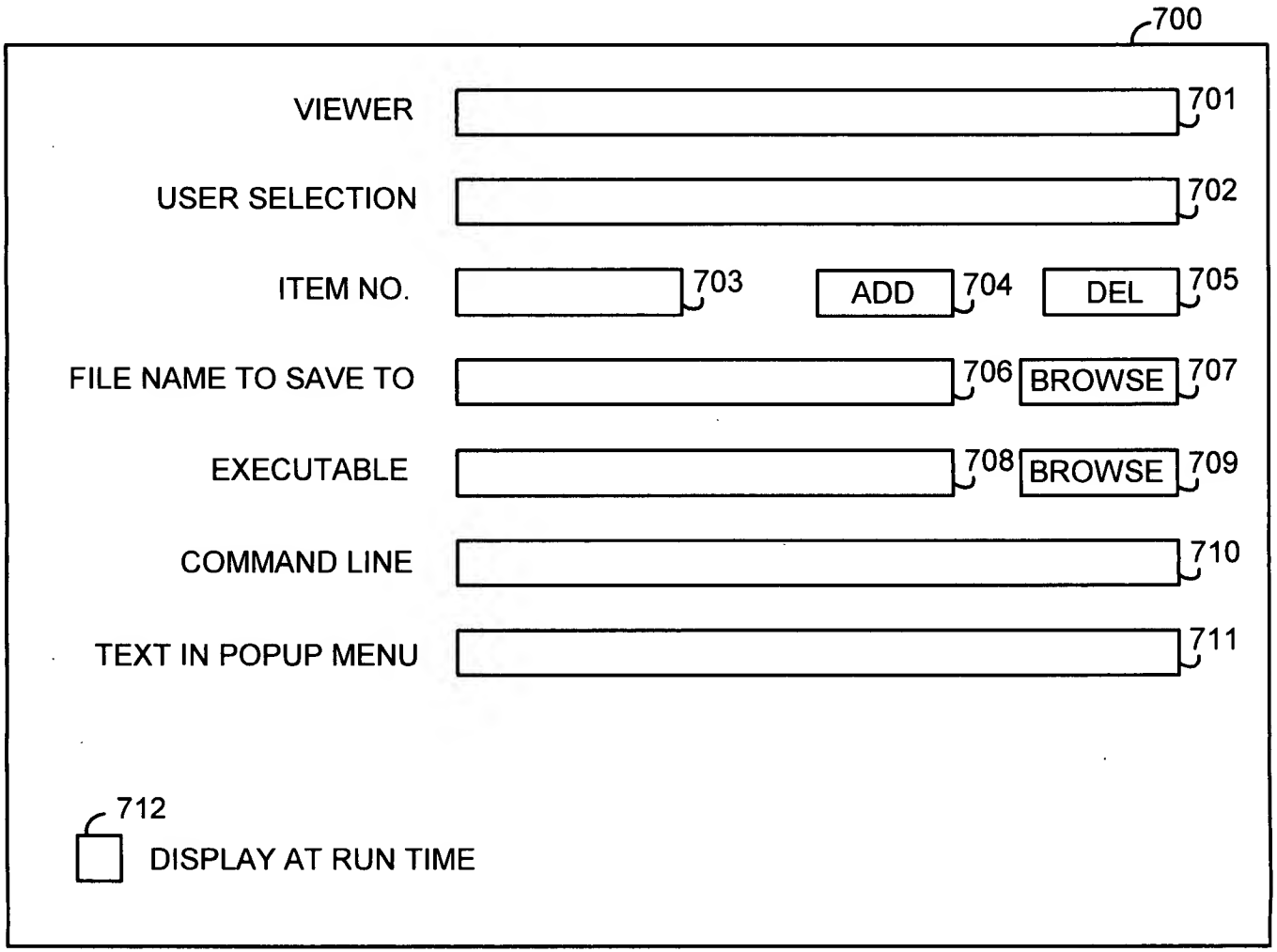

FIG.7

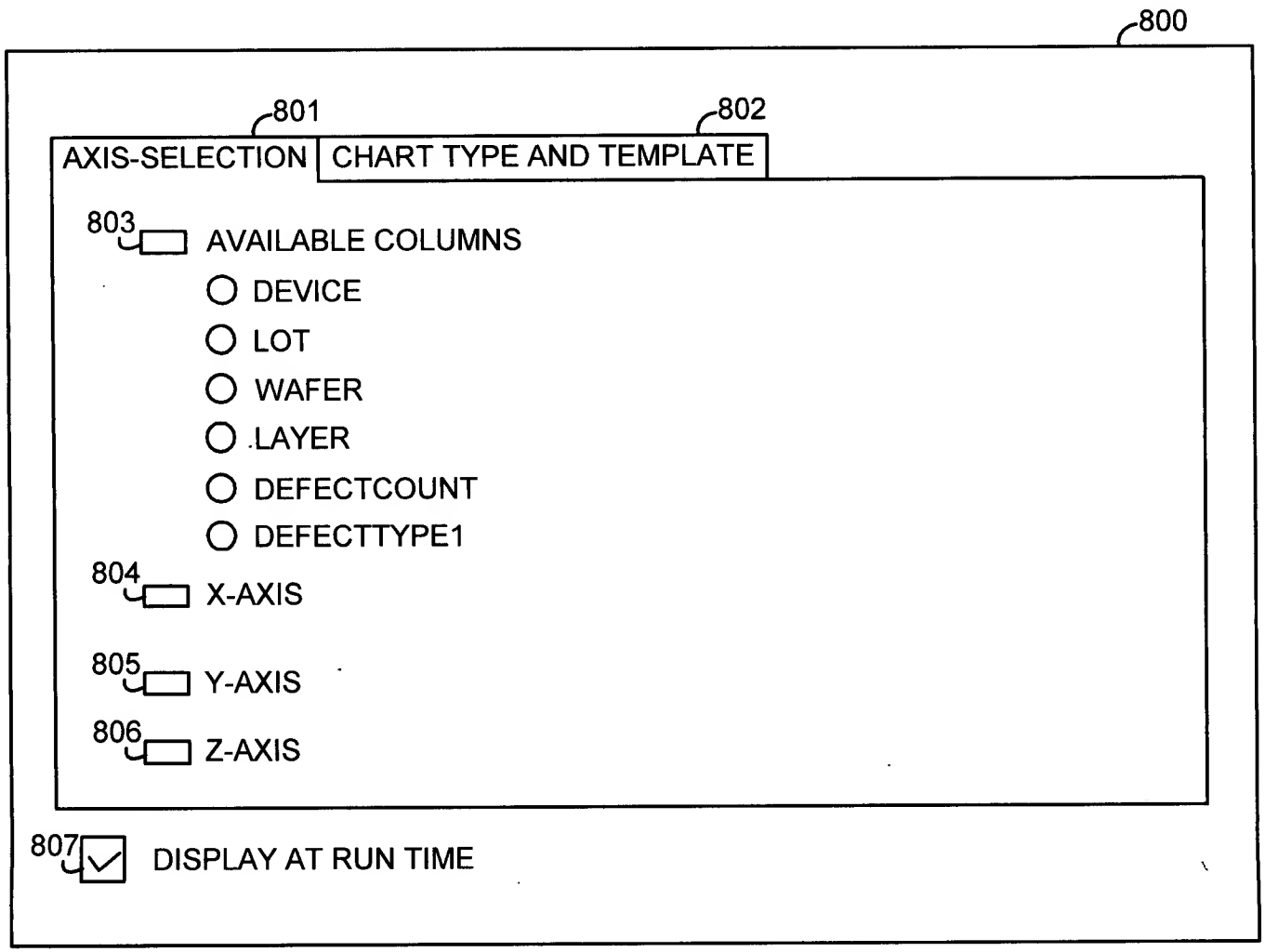
800
801
802
AXIS-SELECTION
CHART TYPE AND TEMPLATE
803
AVAILABLE COLUMNS
DEVICE
LOT
WAFER
LAYER
DEFECTCOUNT
DEFECTTYPE1
804
X-AXIS
805
Y-AXIS
806
Z-AXIS
807
DISPLAY AT RUN TIME

FIG.8

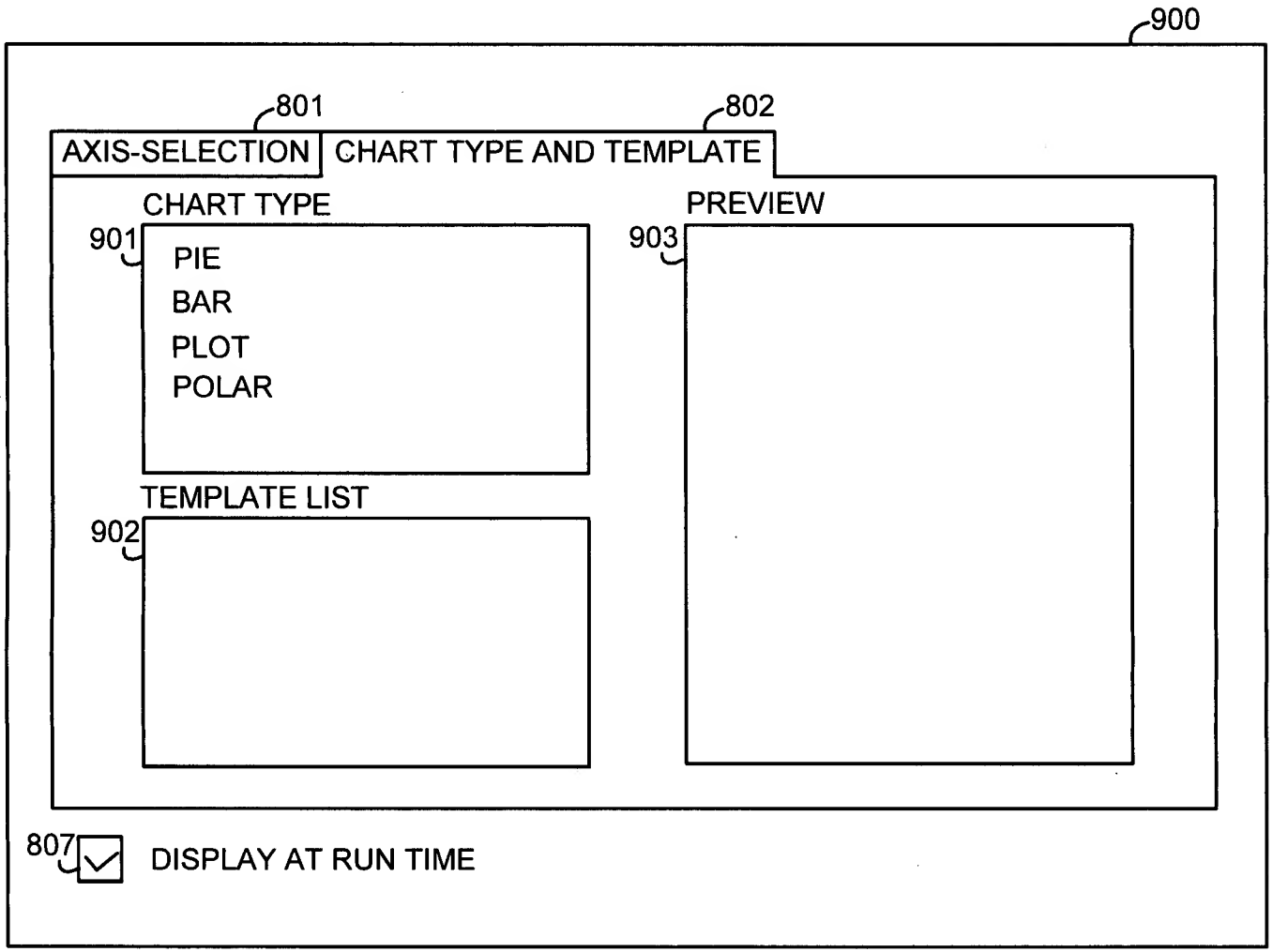
900
801
802
AXIS-SELECTION
CHART TYPE AND TEMPLATE
CHART TYPE
901
PIE
BAR
PLOT
POLAR
PREVIEW
903
TEMPLATE LIST
902
807
DISPLAY AT RUN TIME

FIG.9

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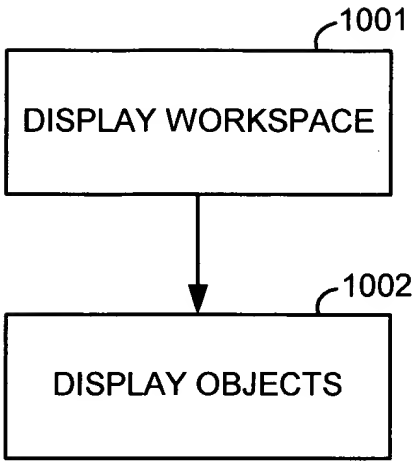

FIG.10